



Title of Change:	Qualification of King Yuan ELECTRONICS CO (KYE) as 2 nd site for AR0237 mPLCC Final Test site.	
Proposed first ship date:	7 December 2018	
Contact information:	Contact your local ON Semiconductor Sales Office or < anna.chou@onsemi.com >	
Samples:	Contact your local ON Semiconductor Sales Office or < PCN.samples@onsemi.com > Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change.	
Additional Reliability Data:	N/A	
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact < PCN.Support@onsemi.com >	
Change Part Identification:	AR0237CSSC12SHRA0 / AR0237CSSC12SPRA0 AR0237CSSC00SHRA0 / AR0237CSSC00SPRA0 AR0237IRSH12SHRA0 / AR0237IRSH12SPRA0 AR0237SRSC12SHRA0	
Change Category:	☐ Wafer Fab Change ☐ Assembly Change ☒ Test Change ☐ Other _____	
Change Sub-Category(s):	☒ Manufacturing Site Addition ☐ Material Change ☐ Datasheet/Product Doc change ☐ Manufacturing Site Transfer ☐ Product specific change ☐ Shipping/Packaging/Marking ☐ Manufacturing Process Change ☐ Other: _____	
Sites Affected:	ON Semiconductor Sites: None	External Foundry/Subcon Sites: KP+KYE
Description and Purpose:		
This Final notification announces the qualification of KYE as 2 nd site for AR0237 mPLCC Final Test site. There are no product material changes as a result of this change. There is no product marking change as a result of this change. The tester platform, test program revision and bin limits are identical between the two locations.		
Reliability Data Summary:		
No reliability test required. 10K safe launch yield monitor between KP and KYE, result is passed.		
Electrical Characteristic Summary:		
Final Test did correlation between KP and KYE, result is passed. Good and bad units tested at both locations correlate 100% for passing (i.e. Bin1) and failing bins. Difference in parametric measurements between the locations are within acceptable error for machine to machine variation.		



List of Affected Parts:

Part Number	Qualification Vehicle
AR0237CSSC00SHRA0-DR	AR0237CSSC12SHRA0-DR
AR0237CSSC00SPRA0-DR	
AR0237CSSC12SHRA0-DR	
AR0237CSSC12SPRA0-DR	
AR0237IRSH12SHRA0-DR	
AR0237IRSH12SPRA0-DR	
AR0237SRSC12SHRA0-DR	